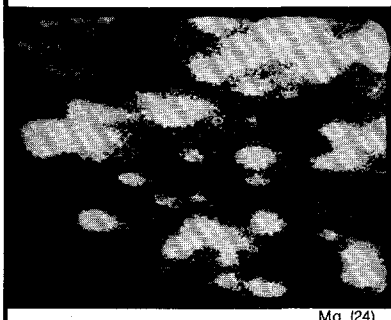


MIQ 156

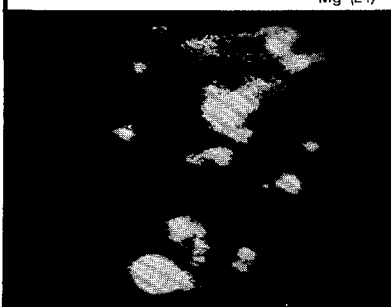
SIMS

ion microprobe, the ideal source for material analyses.

The RIBER MIQ 156 is an ion microprobe which operates under UHV conditions, for enhanced sensitivity (residual gas pressure in 10^{-11} torr range).



Mg (24)



Fe (56)

Ion imaging of a clay sample, after injection of polymer and microtome slicing

problems : depth profiles,
elemental map, mass spectra of polymers,
biological samples, metals, glass,
semiconductors,
geological samples ;
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